

July 2010

FDFME2P823ZT

Integrated P-Channel PowerTrench® MOSFET and Schottky Diode -20 V, -2.6 A, 142 m Ω

Features

- Max $r_{DS(on)} = 142 \text{ m}\Omega$ at $V_{GS} = -4.5 \text{ V}$, $I_D = -2.3 \text{ A}$
- Max $r_{DS(on)}$ = 213 m Ω at V_{GS} = -2.5 V, I_D = -1.8 A
- Max $r_{DS(on)} = 331 \text{ m}\Omega$ at $V_{GS} = -1.8 \text{ V}$, $I_D = -1.5 \text{ A}$
- Max $r_{DS(on)} = 530 \text{ m}\Omega$ at $V_{GS} = -1.5 \text{ V}$, $I_D = -1.2 \text{ A}$
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- **Schottky**: V_F < 0.57 V @ 1A
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600 V (Note 3)
- RoHS Compliant



General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable appliacrions. It features as MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum condution losses.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

Applications

- Battery Charging
- DC-DC Conversion



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Paramet	Parameter			
V_{DS}	Drain to Source Voltage			-20	V
V_{GS}	Gate to Source Voltage			±8	V
ı	Drain Current -Continuous	T _A = 25 °C	(Note 1a)	-2.6	А
ID	-Pulsed			-6	A
D	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1a)	1.4	W
P_{D}	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1b)	0.6	VV
V_{RRM}	Schottky Repetitive Peak Reverse Voltage	;		28	V
I _O	Schottky Average Forward Current			1	Α
T _J , T _{STG}	Operating and Storage Junction Temperate	ure Range	(Note 4)	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1a)	90	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1b)	195	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1c)	110	C/VV
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1d)	234	1

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
3T	FDFME2P823ZT	MicroFET 1.6x1.6 Thin	7 "	8 mm	5000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Parameter Test Conditions		Min	Тур	Max	Units
acteristics					
Drain to Source Breakdown Voltage	$I_D = -250 \mu\text{A}, V_{GS} = 0 \text{V}$	-20			V
Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		-12		mV/°C
Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μА
Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μА
3	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current	tacteristics Drain to Source Breakdown Voltage $I_D = -250 \mu A$, $V_{GS} = 0 V$ Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$, referenced to 25 °C Zero Gate Voltage Drain Current $V_{DS} = -16 V$, $V_{GS} = 0 V$		Incteristics Drain to Source Breakdown Voltage $I_D = -250 \mu A$, $V_{GS} = 0 V$ -20 Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$, referenced to 25 °C -12 Zero Gate Voltage Drain Current $V_{DS} = -16 V$, $V_{GS} = 0 V$	Incteristics Drain to Source Breakdown Voltage $I_D = -250 \mu A$, $V_{GS} = 0 V$ -20 Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$, referenced to 25 °C -12 Zero Gate Voltage Drain Current $V_{DS} = -16 V$, $V_{GS} = 0 V$ -1

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.6	-1.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		2		mV/°C	
r		$V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A}$		95	142		
		$V_{GS} = -2.5 \text{ V}, I_D = -1.8 \text{ A}$		120	213		
	Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -1.5 \text{ A}$		150	331	mΩ	
r _{DS(on)}	Drain to Godice On Resistance	$V_{GS} = -1.5 \text{ V}, I_D = -1.2 \text{ A}$		190	530	11122	
		$V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		128	190		
9 _{FS}	Forward Transconductance	$V_{DS} = -4.5 \text{ V}, I_{D} = -2.3 \text{ A}$		7		S	

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40.V V 0.V	305	405	pF
C _{oss}	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	55	75	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	50	75	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			4.7	10	ns
t _r	Rise Time	V_{DD} = -10 V, I_{D} = -1 A, V_{GS} = -4.5 V, R_{GEN} = 6 Ω		4.8	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, K_{GEN} = 6 \Omega$		33	53	ns
t _f	Fall Time			16	29	ns
Qg	Total Gate Charge	V 40.V I 0.2.A		5.5	7.7	nC
Q _{gs}	Gate to Source Gate Charge	$V_{DD} = -10 \text{ V}, I_{D} = -2.3 \text{ A},$ $V_{GS} = -4.5 \text{ V}$		0.6		nC
Q_{gd}	Gate to Drain "Miller" Charge	VGS - 4.0 V		1.4		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -0.9 \text{ A}$ (Note 2)		-0.8	-1.2	V
t _{rr}	Reverse Recovery Time	I _F = -2.3 A, di/dt = 100 A/μs		16	29	ns
Q_{rr}	Reverse Recovery Charge			4.4	10	nC

Schottky Diode Characteristics

I_	Poverse Leakage	V ₋ = 28 V	T _J = 25 °C	15	100	μΑ
^I R	Reverse Leakage	V _R = 28 V	T _J = 85 °C	0.46	4.7	mA
VE	Forward Voltage	Ι_ = 1 Λ	T _J = 25 °C	0.47	0.57	V
V _F Forward Voltage	I _F = 1 A	$T_J = 85 ^{\circ}\text{C}$	0.45		V	
\/	Forward Voltage	I _F = 500 mA	T _J = 25 °C T _J = 85 °C	0.38	0.48	V
V _F Forward Voltage	Forward voltage	IF = 300 IIIA	$T_J = 85 ^{\circ}\text{C}$	0.33		V

Electrical Characteristics

Notes:

- 1. R_{6JA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{6JC} is guaranteed by design while R_{6JA} is determined by the user's board design.
 - (a) MOSFET $R_{\theta,JA} = 90$ °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
 - (b) MOSFET $R_{\theta JA}$ = 195 °C/W when mounted on a minimum pad of 2 oz copper.
 - (c) Schottky $R_{\theta JA}$ = 110 °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062" thick PCB.
 - (d) Schottky $R_{\theta JA}$ = 234 °C/W when mounted on a minimum pad of 2 oz copper.



 a. 90 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 195 °C/W when mounted on a minimum pad of 2 oz copper.



c. 110 °C/W when mounted on a 1 in² pad of 2 oz copper.



d. 234 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.
- 4. Rating is applicable to MOSFET only.

Typical Characteristics T_J = 25°C unless otherwise noted

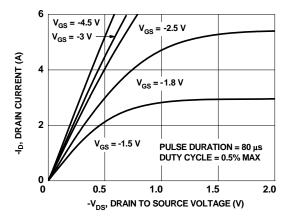


Figure 1. On Region Characteristics

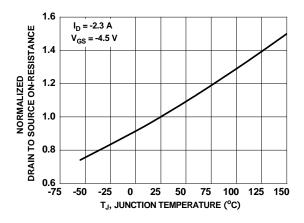


Figure 3. Normalized On Resistance vs Junction Temperature

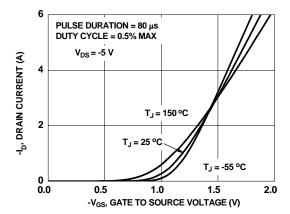


Figure 5. Transfer Characteristics

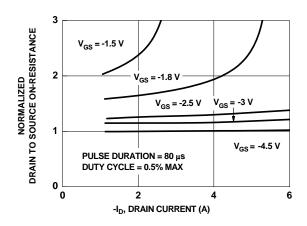


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

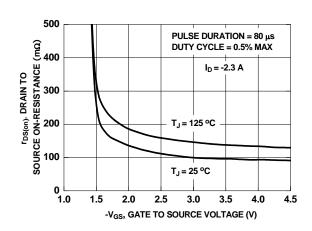


Figure 4. On-Resistance vs Gate to Source Voltage

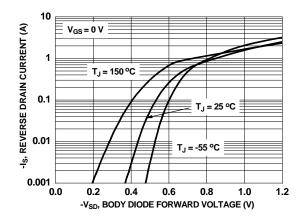


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

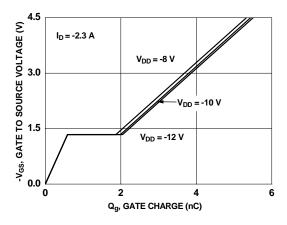


Figure 7. Gate Charge Characteristics

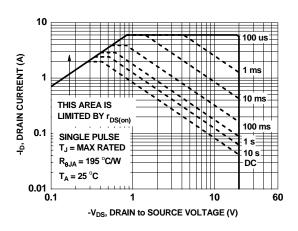


Figure 9. Forward Bias Safe Operating Area

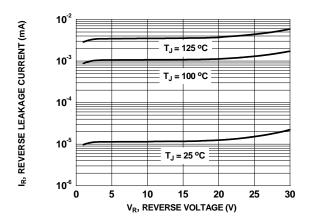


Figure 11. Schottky Diode Reverse Current

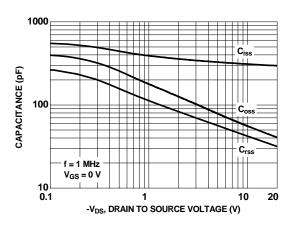


Figure 8. Capacitance vs Drain to Source Voltage

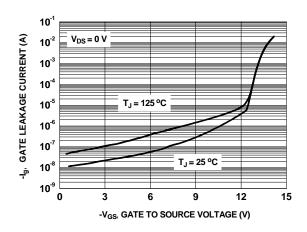


Figure 10. Gate Leakage Current vs Gate to Source Voltage

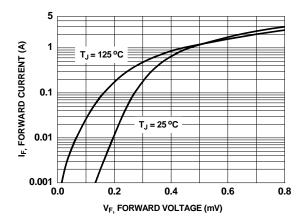


Figure 12. Schottky Diode Forward Voltage

Typical Characteristics $T_J = 25$ °C unless otherwise noted

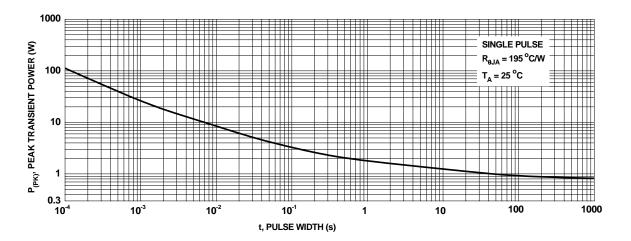


Figure 13. Single Pulse Maximum Power Dissipation

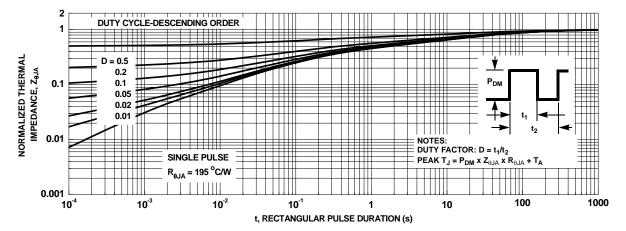
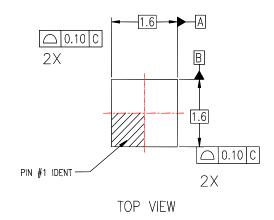
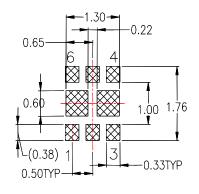


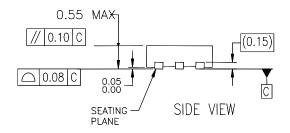
Figure 14. Junction-to-Ambient Transient Thermal Response Curve

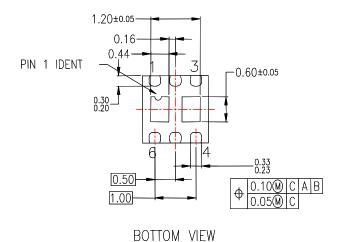
Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN









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